

EAST Search History

10/318,743

| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|-------|------|-------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|--------------------|------------------|---------|------------------|
| L1 | 0 | (analog circuit AND mixed signal circuit AND simulation circuit AND digital signal generator AND input test sequence AND optimization circuit AND monitoir circuit AND circuit under test).clm. | US-PGPUB; USPAT | ADJ | ON | 2006/09/22 18:33 |

10/518,743

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|-----|------|----------------------------------------------------------------------------------------------------|-------------------------------------------------------------------|-----|----|------------------|
| S17 | 9824 | configuration circuit | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/09/22 10:24 |
| S18 | 1 | S14 and S17 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/09/22 10:25 |
| S19 | 14 | S14 and S1 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/09/22 10:39 |
| S24 | 0 | (digit\$4 input test sequence) and (analogue or mixed signal circuit or computer simulation) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/09/22 17:10 |
| S26 | 1041 | digital signal generator | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/09/22 17:11 |
| S27 | 0 | analog\$2 circuit\$1 adj sub system under test | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/09/22 17:19 |
| S28 | 998 | good circuit\$1 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/09/22 17:13 |
| S29 | 1207 | faulty circuit\$1 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/09/22 17:13 |

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|-----|-------|---------------------------------------------------------------------------------------|-------------------------------------------------------------------|-----|----|------------------|
| S30 | 60 | input binary sequence or input digital test sequence or digitized input test sequence | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/09/22 17:14 |
| S31 | 0 | S30 and S26 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/09/22 17:14 |
| S32 | 1 | S30 and (S28 or S29) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/09/22 17:15 |
| S33 | 30180 | analog circuit\$1 or system under test | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/09/22 17:20 |
| S34 | 2 | S33 and S30 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/09/22 17:20 |
| S35 | 0 | S34 and S26 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/09/22 17:20 |
| S36 | 5416 | (test sequence) and (analogue or mixed signal circuit or computer simulation) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/09/22 17:21 |
| S37 | 1 | S36 and S30 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/09/22 17:21 |

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|-----|------|---------------|-------------------------------------------------------------------|-----|----|------------------|
| S38 | 5475 | S36 or S30 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/09/22 17:21 |
| S39 | 342 | S38 and S33 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/09/22 17:21 |
| S40 | 2 | S39 and S28 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/09/22 17:21 |
| S41 | 2 | S39 and S29 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/09/22 17:21 |
| S43 | 3 | S26 and (S39) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | ADJ | ON | 2006/09/22 17:22 |